

Docket No.: 60188-448

PATENT**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of	:	Customer Number: 20277
Keiichi Fujimoto et al.	:	Confirmation Number: 2785
Serial No.: 09/964,480	:	Group Art Unit: 2829
Filed: September 28, 2001	:	Examiner: Paresh Patel
For: SEMICONDUCTOR INTEGRATED CIRCUIT TESTING SYSTEM AND METHOD	:	

AMENDMENT

Mail Stop Fee Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In response to the Office Action dated April 10, 2003, having a three-month shortened statutory period for response set to expire on July 10, 2003, and the petition for a three-month extension of time up to and including October 10, 2003 being filed concurrently herewith, reconsideration of the above-identified application is respectfully requested in view of the following amendment and remarks.

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